

**Search Notes**

Application/Control No.

10/741,824

Examiner

John M. Parker

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2823

**SEARCHED**

Class	Subclass	Date	Examiner
438	652,687	4/13/2006	JMP
438	618	4/13/2006	JMP
257	750,751	4/13/2006	JMP
UPDATED	SEARCH	9/19/2006	JMP

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted George Fourson on search strategy	9/19/2006	JMP
EAST search attached	9/20/2006	JMP